Deep and Machine Learning for Image Processing: Medical and Non-medical Applications

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Deadline for manuscript submissions:
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Message from the Guest Editors

Dear Colleagues,

The new era and recent advances in machine and deep learning approaches have been widely used as indispensable tools in modern artificial intelligence-based image processing systems to perform medical or non-medical tasks. Such systems have proven themselves to be reproducible and have the generalization ability to solve unseen problems and adapt to new conditions.

In this Special Issue, original research articles and reviews are welcome. Research areas may include (but are not limited to) the following:

- Image processing;
- Image localization;
- Object detection;
- Object tracking;
- Medical imaging;
- Image segmentation using deep learning;
- Applying deep learning for image registration;
- AI-based diagnostic systems;
- AI-based predictive systems;
- AI-based healthcare.

We look forward to receiving your contributions.

Special Issue

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Message from the Editor-in-Chief

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